4	Sear	ch Ne	otes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/729,756	CHEN ET AL.
Examiner	Art Unit
Anthony Mackeyey	2624

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	SEAR	CHED	
Class	Subclass	Date	Examiner
382	128-132	2/7/2007	АМ
	294, 296	2/7/2007	AM
	289, 297	2/9/2007	АМ
601	109	2/12/2007	АМ
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
·	DATE	EXMR
Inventor Name Search in PALM	2/12/2007	АМ
EAST Text Search (US-PGPUB, USPAT, USOCR, DERWENT, EPO, JPO, IBM_TDB) - See Search History Printout	2/7/2007	АМ
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